Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination KRISHNAN ET AL.	tent under	
	<b>Examine:</b> Shin, Kyung H	Art Unit 2143		
ORIGINAL	IAL	INTERNATIONAL CLASSIFICATION	CLASSIFICATIO	z
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	IMED
709	225	G 0 6 F 15 / 173		
CROSS REFERENCE(S)	RENCE(S)			
CLASS (ONE SUBCLASS	SUBCLASS PER BLOCK)		,	
714 4				
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Kyung Hye Shin 6/26/2006	90		Total Claims Allowed:	Allowed:
(Assistant Examiner) (Date)			68	
(legal Instruments Examiner)	(Primary Examine	SUPERVISORY FATENT EXAMINER  TECHNOLOGY CENTER 2100	O.G. Print Claim(s) 1	O.G. Print Fig 14

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